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AMENDMENTS TO THE CLAIMS

Please amend Claim 1 as indicated below. Please also cancel Claims 23-42 and 45-46,

without prejudice, as indicated below.

1. (Presently Amended) A method of forming a multijunction solar cell comprising

an upper subcell, a middle subcell, and at least one lower subcell, said upper subcell and said

lower subcell being substantially lattice-matched and said lower subcell being substantially

lattice-mismatched, said method comprising:

providing a growth semiconductor substrate for the epitaxial growth of

semiconductor material;

forming said upper subcell over said growth semiconductor substrate such that

said upper subcell has a first, upper band gap and is substantially lattice-matched to said

growth substrate;

forming said middle subcell over said upper subcell such that said middle subcell

is substantially lattice-matched to said growth substrate and said middle subcell has a

second middle band gap, said first upper band gap being larger than said second middle

band gap; ·

forming said at least one lower subcell over said middle subcell such that said at

least one lower subcell is substantially lattice-mismatched with respect to said growth

substrate and said at least one lower subcell has a third lower band gap, said third lower

band gap being smaller than said second middle band gap;

providing a support structure over said lower subcell; and

removing said growth semiconductor substrate.

2. (Original) The method of Claim 1, wherein said lattice mismatch between said

lower subcell and said growth substrate is about 1% or greater.

3. (Original) The method of Claim 1, wherein said lattice mismatch between said

lower subcell and said growth substrate is about 2% or greater.

4. (Original) The method of Claim 1, wherein said lattice mismatch between said

lower subcell and said growth substrate is about 4% or greater.

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5. (Original) The method of Claim 1, wherein said lattice mismatched between said lower subcell and said growth substrate is about 5% or greater.

- 6. (Original) The method of Claim 1, further comprising removing a portion of said support structure thereby reducing the weight of said support structure after removing said growth semiconductor substrate.
- 7. (Original) The method of Claim 6, wherein said support structure is formed by adhering a thin sheet to a rigid member using a non-permanent adhesive such that said rigid member is detachable from said thin sheet after said support substrate is bonded to said lower subcell and said growth semiconductor substrate is removed.
- 8. (Original) The method of Claim 7, further wherein one side of said thin sheet is metallized to provide electrical bonding to said lower subcell and to provide high reflectance.
- 9. (Original) The method of Claim 1, wherein providing a growth semiconductor substrate for epitaxial growth of semiconductor material comprises providing a substrate selected from the group consisting of a GaAs substrate, a Ge substrate, an InP substrate, and a Si substrate.
- 10. (Original) The method of Claim 1, wherein forming said upper subcell comprises growing Ga_xIn_{1-x}P semiconductor material over said semiconductor growth substrate.
- 11. (Original) The method of Claim 1, wherein forming said middle subcell comprises growing In_vGa_{1-v}As semiconductor material.
- 12. (Original) The method of Claim 1, wherein forming said lower subcell comprises depositing In_vGa_{1-v}As semiconductor material over said middle subcell.
- 13. (Original) The method of Claim 1, wherein forming said lower subcell comprises depositing $Si_{(x)}Ge_{(1-x)}$ semiconductor material over said middle subcell.
- 14. (Original) The method of Claim 1, further comprising forming grading layers between said lower subcell and said middle subcell by growing InGaAs semiconductor material while increasing said In content and decreasing said Ga content to reduce stress in said lower subcell resulting from mismatch of lattice spacing.
- 15. (Original) The method of Claim 1, further comprising forming grading layers between said lower subcell and said middle subcell by growing In_yGa_{1-y}As to reduce stress in said lower subcell resulting from mismatch of lattice spacing.

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- 16. (Original) The method of Claim 1, further comprising forming a parting layer between said growth semiconductor substrate and said top subcell.
- 17. (Original) The method of Claim 16, further comprising preferentially etching said parting layer so as to remove said growth semiconductor substrate substantially intact for reuse.
- 18. (Original) The method of Claim 1, further comprising reusing said growth semiconductor substrate for epitaxial growth of semiconductor material after said step of removing said growth semiconductor substrate.
- 19. (Original) The method of Claim 1, wherein said semiconductor growth substrate is removed by etching the substrate.
- 20. (Original) The method of Claim 1, wherein first and second lower subcells are formed, said first lower subcell having a larger band gap than said second lower subcell.
- 21. (Original) The method of Claim 20, wherein said first lower subcell, said second lower subcell, and said middle subcell are formed by growing InGaAs based material and said upper subcell is formed by growing InGaP based material.
- 22. (Original) The method of Claim 21, further comprising forming grading layers between said first and second lower subcells by growing InGaAs semiconductor material while increasing said In content and decreasing said Ga content to reduce stress in said lower subcell resulting from mismatch of lattice spacing.
 - 23. (Canceled)
 - 24. (Canceled)
 - 25. (Canceled)
 - 26. (Canceled)
 - 27. (Canceled)
 - 28. (Canceled)
 - 29. (Canceled)
 - 30. (Canceled)
 - 31. (Canceled)
 - 32. (Canceled)
 - 33. (Canceled)
 - 34. (Canceled)
 - 35. (Canceled)

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- 36. (Canceled)
- 37. (Canceled)
- 38. (Canceled)
- 39. (Canceled)
- 40. (Canceled)
- 41. (Canceled)
- 42. (Canceled)
- 43. (Original) A method of forming a multijunction solar cell comprising a high band gap substantially unstrained subcell and at least one lattice-mismatched low band gap subcell, the method comprising:

providing a growth semiconductor substrate for the epitaxial growth of semiconductor material;

forming the high band gap subcell over the growth semiconductor substrate, the high band gap subcell having a first high band gap.

forming the at least one low band gap subcell over the high band gap subcell, the low band gap subcell having a second low band gap, the first high band gap being larger than the second low band gap, said growth substrate and said low band gap subcell having substantial lattice mismatch;

providing a support substrate over the low band gap subcell; and removing the growth semiconductor substrate.

- 44. (Original) The method of Claim 43, wherein said lattice mismatch between said low band gap subcell and said growth substrate is at least about 1%.
 - 45. (Canceled)
 - 46. (Canceled)